

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/628,259	HWU ET AL.	
Examiner	Art Unit	
IOHN PAK	1616	

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Class	Subclass	Date	Examiner
UPVated	1:)	
424	602-606 617,630	1/06	
	632 637-639		/
	641-642 646-650		
	652,654		
	655,665 669-671 675-682) (M) .
	685 692-698	17	
V	722		
514	492-494 498-502		
	505,553 557-560		
	574		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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